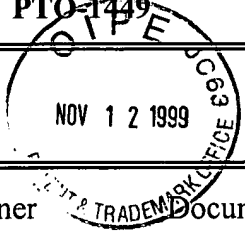


INFORMATION DISCLOSURE STATEMENT PTO-1449	Atty. Docket No. 970150A	Serial No. 09/228,148
	Applicants: Yasunori INOUE et al.	
	Filing Date: January 11, 1999	Group Art Unit: 2812



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Examiner Initial	Document No.	Name	Date	Class	Subclass	Filing Date (If appropriate)	
<u>KB</u>	AA	5,930,624	Murata et al.	7-27-99	438	253	1-26-98
<u>KB</u>	AB	4,962,052	Asayama et al.	10-09-90	437	31	

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<u>KB</u> AC 62-60242	3-16-87	Japan	Abstract
<u>KB</u> AD 1-199456	8-10-89	Japan	Abstract
<u>KB</u> AE 3-101130	4-25-91	Japan	Abstract
<u>KB</u> AF 5-74963	3-26-93	Japan	Abstract
<u>KB</u> AG 6-349950	12-22-94	Japan	Abstract
<u>KB</u> AH 2-26055	1-29-90	Japan	Abstract
<u>KB</u> AI 4-234149	8-21-92	Japan	Abstract
<u>KB</u> AJ 7-99195	4-11-95	Japan	Abstract
<u>KB</u> AK 2-253643	10-12-90	Japan	Abstract
<u>KB</u> AL 2-7451	1-11-90	Japan	Abstract
<u>KB</u> AM 8-17770	1-19-96	Japan	Abstract
<u>KB</u> AN 6-275229	9-30-94	Japan	Abstract
<u>KB</u> AO 5-198523	8-06-93	Japan	Abstract
<u>KB</u> AP 4-317358	11-09-92	Japan	Abstract

Examiner <u>KB</u> EADN	Date Considered <u>10/3/00</u>
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PTO-1449

Atty. Docket No. 970150A

Serial No 09/228,148

Applicant(s): INOUE et al.

Filing Date: January 11, 1999

Group Art Unit: 2823

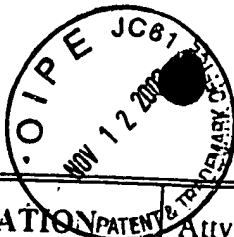
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Examiner Initial		Document No.	Name	Date	Class	Subclass	Filing Date (If appropriate)
<i>flm</i>	AA	5,818,068	Sasaki, et al.	10/98	257	59	09/21/1998
<i>gm</i>	AB	6,001,745	Tu, et al.	12/99	438	78	04/14/1999
	AC						
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	AI						
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	Document No.	Date	Country	Translation (Yes or No)
	AK 9-312339	12/21/97	Japan	Abstract
	AL 9-246375	9/19/97	Japan	Abstract
	AM EP 0 602 607 A1	6/22/94	Europe	Yes
	AN 0179563	11/27/98	Korea	Abstract
	AO			
	AP			
	AQ			



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	Applicant(s): INOUE et al.	
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<i>Her</i>	AA 5,818,068	Sasaki, et al.	10/98	257	59	09/21/1998
<i>JEM</i>	AB 6,001,745	Tu, et al.	12/99	438	782	04/14/1999
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	AE					
	AF					
	AG					
	AH					
	AI					
	AJ					

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Document No.	Date	Country	Translation (Yes or No)
AK 9-312339	12/21/97	Japan	Abstract
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AM EP 0 602 607 A1	6/22/94	Europe	Yes
AN 0179563	11/27/98	Korea	Abstract
AO			
AP			
AQ			

INFORMATION DISCLOSURE CITATION PTO-1449	Atty. Docket No. 970150A	Serial No. 09/228,148
	Applicant(s): Yasunori INOUE	
	Filing Date: January 11, 1999	Group Art Unit: 2814

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Examiner Initial	Document No.	Name	Date	Class	Subclass	Filing Date (If appropriate)
<u>KE</u>	AA	5,341,026	Harada et al.	8/23/94	257	758
<u>KE</u>	AB	5,373,192	Eguchi	12/13/94	257	758
<u>KE</u>	AC	5,523,616	Den	6/04/96	257	758
<u>KE</u>	AD	5,519,254	Tabara	5/21/96	257	758
<u>KE</u>	AE	5,387,812	Forouhi et al.	2/07/95	257	758
<u>KE</u>	AF	5,310,700	Lien et al.	5/10/94	257	758

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Document No.	Date	Country	Translation (Yes or No)
<u>KE</u> AG 2-235358	09/18/90	JAPAN	Partial
<u>KE</u> AH 5-226334	09/03/93	JAPAN	Partial
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<u>KE</u>	AL	Sze, <u>Physics of Semiconductor Devices</u> , 2nd Ed. 1981, p. 393.
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	Applicant(s): Yasunori INOUE	
	Filing Date: January 11, 1999	Group Art Unit: 2814

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Examiner Initial	Document No.	Name	Date	Class	Subclass	Filing Date (If appropriate)
<u>KB</u>	AA	4,668,973	Dawson et al.	5/26/87	257	634
<u>KB</u>	AB	4,676,867	Elkins et al.	6/30/87	257	752
<u> </u>	AC					
<u> </u>	AD					
<u> </u>	AE					
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<u> </u> AH			
<u> </u> AI			
<u> </u> AJ			
<u> </u> AK			

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<u> </u> AL	
<u> </u> AM	

Examiner <u>Kurt EATON</u>	Date Considered <u>10/3/88</u>
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**INFORMATION
DISCLOSURE
CITATION
PTO-1449**

Atty. Docket No. 970150A

Serial No. 09/228,148

Applicant(s): Y. INOUE et al.

Filing Date: January 11, 1999

Group Art Unit: 2812

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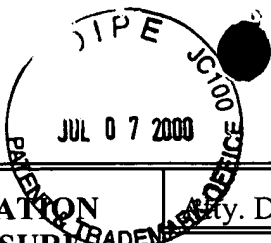
	AY	Wang et al., "A Study of Plasma Treatments on Siloxane SOB," IEEE VMIC Conference, June 7-8, 1994, pp. 101-107
	AZ	Chiang et al., "Defects Study on Spin-on Glass Planarization Technology, IEEE VMIC Conference, June 15-16, 1987, pp. 404-412.
	BA	Lai Juh Chen, et al., "Fluorine Implanted Treatment (FIT) SOG for the Non Etchback Intermetal Dielectric," IEEE VMIC Conference, June 7-8, 1994, pp. 81-86.
<i>VB</i>	BB	Moriya et al., "Modification Effects in Ion-Implanted SiO₂ Spin-on Glass," J. Electrochem. Soc., Vol. 140, No. 5, May 1993, pp. 1442-1450. <i>disregard mark</i>
	BC	Matsuura et al., "An Advanced Interlayer Dielectric System with Partially Converted Organic SOG Using Plasma Treatment," IEEE VMIC Conference, June 8-9, 1993, pp. 113-115.
<i>VB</i>	BD	Ishida et al., "Mechanism for ALSiCu alloy Corrosion," <u>Jpn. J. Appl. Phys.</u> , Vol. 31 (1992), pp. 2045-2048.
	DE	Doki et al., "Moisture-Blocking Mechanism of ECR Plasma," IEEE VMIC Conference, June 7-8, 1994, pp. 235-239.
	DF	Shimokawa et al., "Suppression of MOSFET hot carrier degradation by P-SiO₂ underlayer," The Institute of Electronics, Information and Communication Engineers, Technical Report of IEICE, SDM92-133 (1992-12), pp. 89-94.
<i>VB</i>	BG	Murase et al., "Dielectric Constant of Silicon Dioxide Deposited by Atmospheric-Pressure Chemical Vapor Deposition Using Tetraethylorthosilicate and Ozone," <u>Jpn. J. Appl. Phys.</u> , Vol. 33 (1994), pp. 1385-1389.

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	Applicant(s): Y. INOUE et al.	
	Filing Date: January 11, 1999	Group Art Unit: 2812

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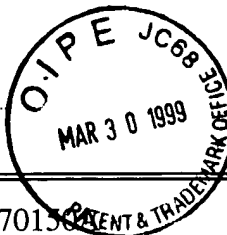
Examiner Initial	Document No.	Name	Date	Class	Subclass	Filing Date (If appropriate)
<u>VB</u>	AA	6,013,578	Jun	01/2000	438	687
<u>VB</u>	AB	5,963,827	Enomoto et al.	10/1999	438	629
<u>VB</u>	AC	5,786,273	Hibi et al.	07/1998	438	637
<u>VB</u>	AD	5,153,680	Naito et al.	10/1992	357	8
<u>VB</u>	AE	3,747,203	Shannon	07/1973	29	578
<u>VB</u>	AF	5,166,768	Ito	11/1992	257	523
<u>VB</u>	AG	4,775,550	Chu et al.	10/1988	427	38
<u>VB</u>	AH	4,885,262	Ting et al.	12/1989	437	231
<u>VB</u>	AI	4,983,546	Hyun et al.	01/1991	437	231
<u>VB</u>	AJ	5,003,062	Yen	03/1991	437	231
<u>VB</u>	AK	5,106,787	Yen	04/1992	437	231
<u>VB</u>	AL	5,352,630	Kim et al.	10/1994	437	195
<u>VB</u>	AM	5,549,786	Jones et al.	08/1996	156	662.1
<u>VB</u>	AN	4,984,055	Okumura et al.	01/1991	257	644
<u>VB</u>	AO	5,270,259	Itoh et al. —	12/1993	437	235
<u>VB</u>	AP	5,468,684	Yoshimori et al.	11/1995	437	228
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<u>VB</u>	AR	4,218,495 A1	12/10/92	Germany	
<u>VB</u>	AS	1-307247	12/12/89	Japan	
<u>VB</u>	AT	5-226334	03/09/93	Japan	
<u>VB</u>	AU	2-101532 -	08/13/90	Japan	
<u>VB</u>	AV	2-235358 -	09/18/90	Japan	
<u>VB</u>	AW	4-307934 (A)	10/30/92	Japan	
<u>VB</u>	AX	8-64561	3/8/96	Japan	

NO
ABSTRACT

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INFORMATION DISCLOSURE CITATION PTO-1449	Atty. Docket No. 970156	Serial No. 09/228,148
	Applicant(s): INOUE et al.	
	Filing Date: January 11, 1999	Group Art Unit:

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Examiner Initial	Document No.	Name	Date	Class	Subclass	Filing Date (If appropriate)
<u>VB</u>	AA	5,607,880	SUZUKI et al.	3/04/97	437	195
<u>VB</u>	AB	5,429,990	LIU et al.	7/04/95	437	190
<u>VB</u>	AC	5,192,697	LEONG	3/09/93	437	37
_____	AD					
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Document No.	Date	Country	Translation (Yes or No)
_____	AF		
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_____	AH		
_____	AI		
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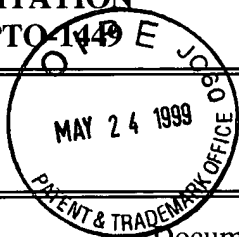
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INFORMATION DISCLOSURE CITATION PTO-1449 E	Atty. Docket No. 970150A	Serial No. 09/228,148
	Applicant(s): INOUE et al.	
	Filing Date: January 11, 1999	Group Art Unit:



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Examiner Initial	Document No.	Name	Date	Class	Subclass	Filing Date (If appropriate)
<u>KA</u>	AA	5,753,975	Matsuno	5/19/98	257	751
<u>KA</u>	AB	5,702,568	Shin et al.	12/30/97	156	644.1
<u>KB</u>	AC	5,665,845	Allman	9/09/97	528	5
<u>KB</u>	AD	5,514,910	Koyama	5/07/96	257	768
<u>KA</u>	AE	5,479,054	Tottori	12/26/95	257	752
<u>KB</u>	AF	5,087,589	Chapman et al.	2/11/92	437	195
<u>KB</u>	AG	5,084,412	Nakasaki	1/28/92	437	189

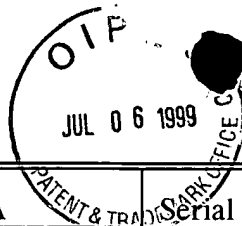
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	Applicant(s): INOUE et al.		
	Filing Date: January 11, 1999		Group Art Unit: 2812

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<u>16</u>	AA	5,866,476	Choi et al.	2/02/99		
<u>16</u>	AB	5,855,962	Cote et al.	2/05/99		
<u>16</u>	AC	5,817,582	Maniar	10/06/98		
<u>16</u>	AD	5,569,618	Matsubara	10/29/96		
<u>16</u>	AE	5,496,776	Chien et al.	3/05/96		
<u>16</u>	AF	5,192,697	Leong	3/09/93		
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<u>16</u> AI 9-104698	11/13/98	Japan	Abstract only
<u>16</u> AJ 9-58062	3/12/97	Japan	No
<u>16</u> AK 9-8949	1/21/97	Japan	No
<u>16</u> AL 8-241891	9/17/96	Japan	No

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<u>16</u>	AM	Japanese Patent Laying-Open 59-017243 (abstract).
<u>16</u>	AN	Japanese Patent Laying-Open No. 58-031519 (abstract).
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